# IEC 63185

Edition 2.0 2025-03

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

## Measurement of the complex permittivity for low-loss dielectric substrates balanced-type circular disk resonator method

**Méthode du résonateur symétrique à disque circulaire pour mesurer la permittivité complexe des substrats diélectriques à faible perte**

IEC Secretariat
3, rue de Varembé
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

**About the IEC**
The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

**About IEC publications**
The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigendum or an amendment might have been published.

**IEC publications search - webstore.iec.ch/advsearchform**
The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee, …). It also gives information on projects, replaced and withdrawn publications.

**IEC Just Published - webstore.iec.ch/justpublished**
Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and once a month by email.

**IEC Customer Service Centre - webstore.iec.ch/csc**
If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: sales@iec.ch.

**IEC Products & Services Portal - products.iec.ch**
Discover our powerful search engine and read freely all the publications previews, graphical symbols and the glossary. With a subscription you will always have access to up to date content tailored to your needs.

**Electropedia - www.electropedia.org**
The world's leading online dictionary on electrotechnology, containing more than 22 500 terminological entries in English and French, with equivalent terms in 25 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.

---

**A propos de l'IEC**
La Commission Electrotechnique Internationale (IEC) est la première organisation mondiale qui élabore et publie des Normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

**A propos des publications IEC**
Le contenu technique des publications IEC est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

**Recherche de publications IEC - webstore.iec.ch/advsearchform**
La recherche avancée permet de trouver des publications IEC en utilisant différents critères (numéro de référence, texte, comité d'études, …). Elle donne aussi des informations sur les projets et les publications remplacées ou retirées.

**IEC Just Published - webstore.iec.ch/justpublished**
Restez informé sur les nouvelles publications IEC. Just Published détaille les nouvelles publications parues. Disponible en ligne et une fois par mois par email.

**Service Clients - webstore.iec.ch/csc**
Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions contactez-nous: sales@iec.ch.

**IEC Products & Services Portal - products.iec.ch**
Découvrez notre puissant moteur de recherche et consultez gratuitement tous les aperçus des publications, symboles graphiques et le glossaire. Avec un abonnement, vous aurez toujours accès à un contenu à jour adapté à vos besoins.

**Electropedia - www.electropedia.org**
Le premier dictionnaire d'électrotechnologie en ligne au monde, avec plus de 22 500 articles terminologiques en anglais et en français, ainsi que les termes équivalents dans 25 langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International (IEV) en ligne.

IEC 63185

Edition 2.0 2025-03

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

## Measurement of the complex permittivity for low-loss dielectric substrates balanced-type circular disk resonator method

## Méthode du résonateur symétrique à disque circulaire pour mesurer la permittivité complexe des substrats diélectriques à faible perte

INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

ICS 33.120.30

ISBN 978-2-8327-0311-3

CONTENTS

INTERNATIONAL ELECTROTECHNICAL COMMISSION

_____

# MEASUREMENT OF THE COMPLEX PERMITTIVITY FOR LOW-LOSS DIELECTRIC SUBSTRATES BALANCED-TYPE CIRCULAR DISK RESONATOR METHOD

## FOREWORD

1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
6) All users should ensure that they have the latest edition of this publication.
7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
9) IEC draws attention to the possibility that the implementation of this document may involve the use of (a) patent(s). IEC takes no position concerning the evidence, validity or applicability of any claimed patent rights in respect thereof. As of the date of publication of this document, IEC had not received notice of (a) patent(s), which may be required to implement this document. However, implementers are cautioned that this may not represent the latest information, which may be obtained from the patent database available at https://patents.iec.ch. IEC shall not be held responsible for identifying any or all such patent rights.

IEC 63185 has been prepared by subcommittee 46F: RF and microwave passive components, of IEC technical committee 46: Cables, wires, waveguides, RF connectors, RF and microwave passive components and accessories. It is an International Standard.

This second edition cancels and replaces the first edition published in 2020. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) the upper limit of the applicable frequency range has been extended from 110 GHz to 170 GHz;
b) circular disk resonators used for the measurements now include one with waveguide interfaces;

c) in calculating the complex permittivity from the measured resonant properties, the fringing fields are now accurately taken into account based on the mode-matching analysis.

The text of this International Standard is based on the following documents:

| Draft | Report on voting |
|---|---|
| 46F/699/FDIS | 46F/702/RVD |

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn, or
- revised.

# MEASUREMENT OF THE COMPLEX PERMITTIVITY FOR LOW-LOSS DIELECTRIC SUBSTRATES BALANCED-TYPE CIRCULAR DISK RESONATOR METHOD

## 1 Scope

This document relates to a measurement method for complex permittivity of dielectric substrates at microwave and millimeter-wave frequencies. This method has been developed to evaluate the dielectric properties of low-loss materials used in microwave and millimeter-wave circuits and devices. It uses higher-order modes of a balanced-type circular disk resonator and provides broadband measurements of dielectric substrates by using one resonator, where the effect of excitation holes and that of fringing fields are taken into account accurately on the basis of the mode-matching analysis.

In comparison with the conventional method described in IEC 62810 and IEC 61338-1-3, this method has the following characteristics:

- the values of the relative permittivity $\varepsilon_r'$ and loss tangent $\tan\delta$ normal to dielectric plate samples can be measured accurately and non-destructively;
- this method presents broadband measurements by using higher-order modes by one resonator;
- this method is applicable for the measurements under the following conditions:
  - frequency: 10 GHz ≤ $f$ ≤ 170 GHz;
  - relative permittivity: 1 ≤ $\varepsilon_r'$ ≤ 10;
  - loss tangent: $10^{-4} \leq \tan\delta \leq 10^{-2}$.

## 2 Normative references

There are no normative references in this document.

## 3 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- IEC Electropedia: available at https://www.electropedia.org/
- ISO Online browsing platform: available at https://www.iso.org/obp

## 4 Measurement parameters

The measurement parameters are defined as follows:

$$\varepsilon_r = \varepsilon_r' - j\varepsilon_r'' \tag{1}$$